

Compressed Sensing with Fourier Measurements

November 8, 2017

Random Gaussian matrices

Given $x \in \mathbb{C}^{N \times N}$, let $\hat{x} = U_{\text{Haar}} \hat{z}$ where

$$\hat{z} \in \operatorname{argmin}_{z \in \mathbb{C}^{N \times N}} \|z\|_1 \quad \text{subject to} \quad \left\| AU_{\text{Haar}}^{-1} z - y \right\|_2 \leq \eta.$$

x



\hat{x}



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x



\hat{x}



Problem: No fast transforms for Gaussian/Bernoulli random matrices, and they are expensive to store. E.g. To store a Gaussian matrix for sampling 512×512 images at 5% subsampling would require 25GB.

Fourier Sampling in Inverse Problems

Many imaging problems* are modelled by the Fourier transform

$$\mathcal{F}f(\omega) = \int_{\mathbb{R}^d} f(x) e^{-2\pi i \omega \cdot x} dx,$$

or the Radon transform $\mathcal{R}f : \mathbf{S}^{d-1} \times \mathbb{R} \rightarrow \mathbb{C}$ (where \mathbf{S}^{d-1} denotes the sphere)

$$\mathcal{R}f(\theta, \rho) = \int_{\langle x, \theta \rangle = \rho} f(x) dm(x),$$

where dm denotes Lebesgue measure on the hyperplane $\{x : \langle x, \theta \rangle = \rho\}$.

- ▶ Fourier slice theorem \Rightarrow both problems can be viewed as the problem of reconstructing f from pointwise samples of its Fourier transform.

$$g = \mathcal{F}f, \quad f \in L^2(\mathbb{R}^d). \quad (1)$$

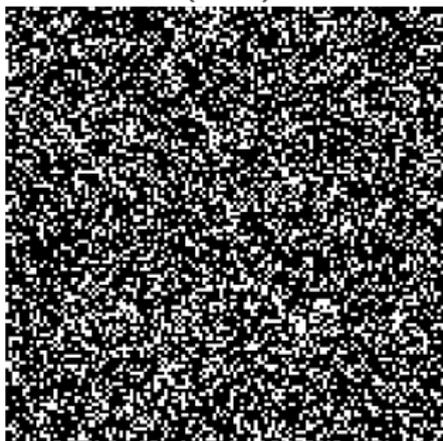
* Magnetic Resonance Imaging (MRI), X-ray Computed Tomography, Electron Microscopy, Radio interferometry, ...

Random Fourier sampling and the RIP

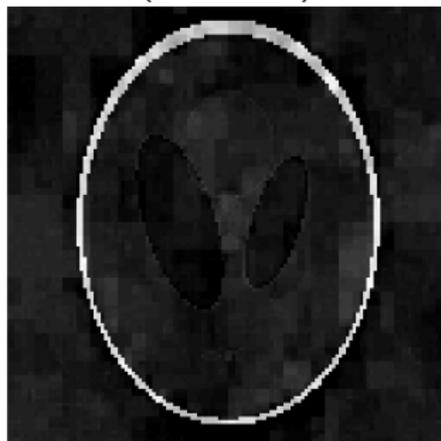
M. Rudelson and R. Vershynin (2008) proved that $P_{\Omega}U_{df}$ satisfies $\delta_s(P_{\Omega}U_{df}) \leq \delta$ with high probability provided that Ω consists of m indices chosen uniformly at random such that

$$m \geq C\delta^{-2}s \ln^4(N).$$

Ω (30%)



\hat{x} (128×128)



NB: $\ln^4(N)$ is large in practice. In our case, we are interested in 128×128 images, if $s = 0.05N^2$ then $s \ln^4(N^2) \approx 7.26 \times 10^6 > N^2$.

Uniform vs Nonuniform recovery

The results we have seen so far are **uniform recovery guarantees**: *Under certain conditions, with high probability, we can recover all s -sparse vectors.*

There is another kind of statement, namely **nonuniform recovery guarantees**: *Let x be a fixed sparse vector. Then, under certain conditions, with high probability, x can be recovered.*

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Theorem (Candés & Plan, 2011): *Let $U \in \mathbb{C}^{N \times N}$ be an isometry. If α is s -sparse, then solving*

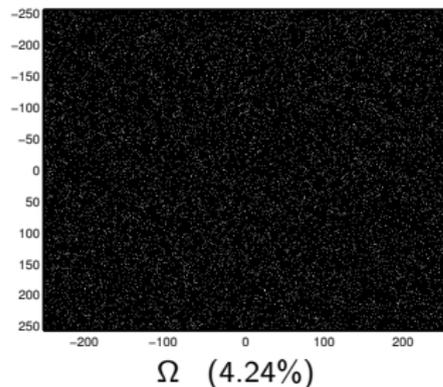
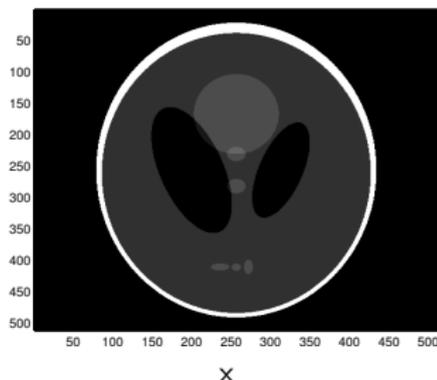
$$\min_{\beta \in \mathbb{C}^N} \|\beta\|_1 \quad \text{subject to } P_\Omega U\beta = P_\Omega U\alpha$$

*recovers α with probability exceeding $(1 - \epsilon)$ if Ω is chosen **uniformly at random** such that it is of cardinality*

$$m \gtrsim s \cdot \log(N/\epsilon) \cdot \mu(U) \cdot N$$

*where the **coherence** is $\mu(U) := \max_{j,k=1,\dots,N} |U_{j,k}|^2 \in [N^{-1}, 1]$.*

An intriguing experiment (Candès, Romberg & Tao, 2006)



$$\min_{z \in \mathbb{C}^{N \times N}} \|Dz\|_1 \quad \text{subject to } P_\Omega Uz = P_\Omega Ux$$

$$\blacktriangleright Uz = \left(N^{-1} \sum_{j_1=1}^N \sum_{j_2=1}^N z_{j_1, j_2} e^{i2\pi(k_1 j_1 + k_2 j_2)} \right)_{k_1, k_2 = -\lfloor N/2 \rfloor, \dots, \lceil N/2 \rceil - 1}$$

$$\blacktriangleright Dz = D_1 z + iD_2 z \quad \text{where}$$

$$D_1 z = (x_{k+1, j} - z_{k, j})_{k, j=1}^N, \quad D_2 z = (z_{k, j+1} - z_{k, j})_{k, j=1}^N$$

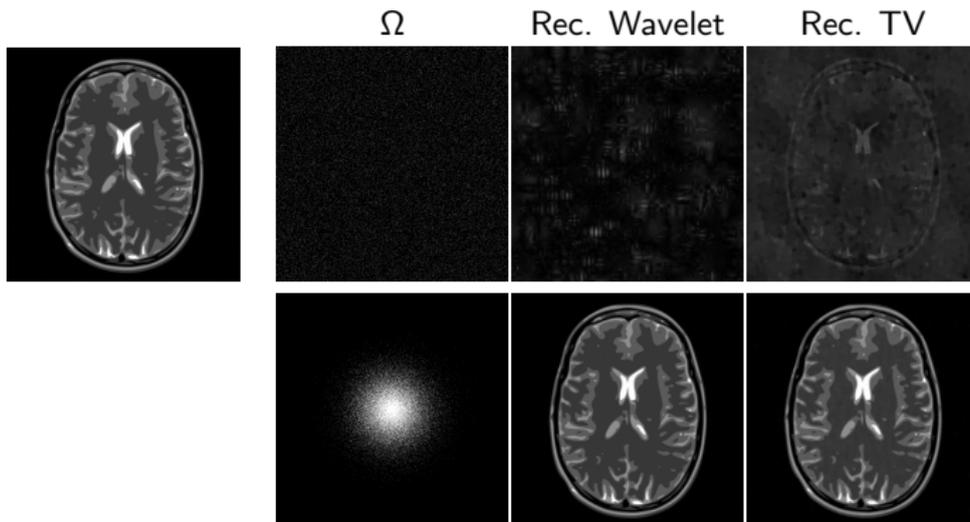
with $z_{N+1, j} := z_{1, j}$ and $z_{k, N+1} := z_{k, 1}$.

Variable Density Sampling

5% sampling for 1024×1024 phantom

In the Fourier-wavelets case: $\mu(U_{dft} U_{dwt}^{-1}) = 1$.

Lustig, Donoho & Pauli '07, Lustig et al. '08: Sample more densely at low Fourier frequencies and less at higher Fourier frequencies.



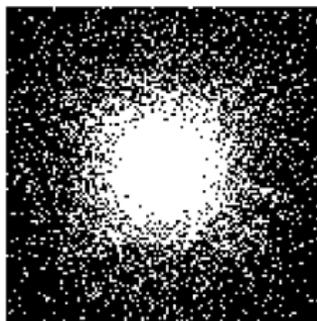
Why does VDS work?

Sparsity and the Flip Test

*In standard CS, the only signal structure considered is **sparsity**. In contrast, the flip test will demonstrate that we must look beyond sparsity.*

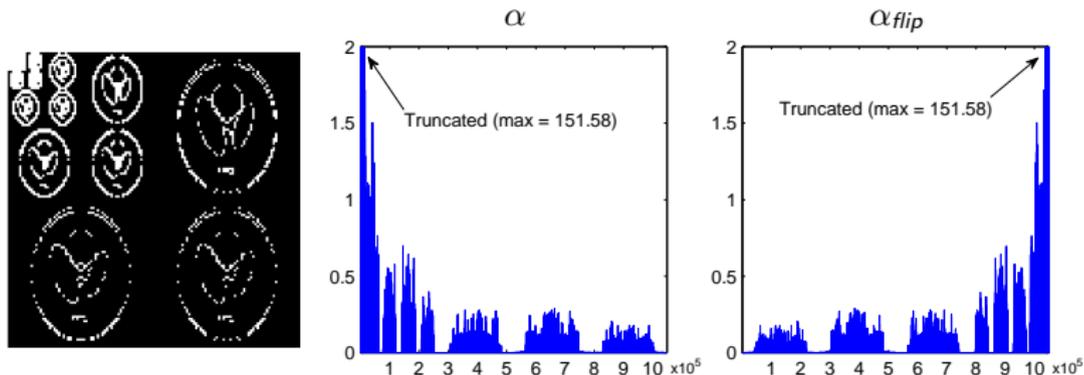
Consider the reconstruction of x from $P_{\Omega}U_{df}x$ by solving

$$\min_z \|z\|_1 \text{ subject to } P_{\Omega}U_{df}U_{dw}^{-1}z = P_{\Omega}U_{df}x.$$



Sparsity and the Flip Test

Let α be the wavelet coefficients of x . Let $\alpha^{flip} = (\alpha_N, \dots, \alpha_1)$ and $x^{flip} = U_{dw}^{-1} \alpha^{flip}$.



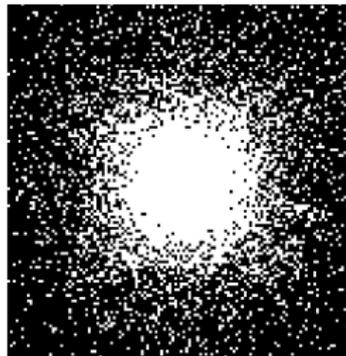
For the same Ω , let

$$\tilde{\alpha} \in \arg \min_{\beta} \|\beta\|_1 \text{ subject to } P_{\Omega} U_{df} U_{dw}^{-1} \beta = P_{\Omega} U_{df} x^{flip}$$

If sparsity was enough, then the wavelet coefficients $\tilde{\alpha}$ should be α^{flip} , we should be able to recover x as $U_{dw}^{-1} \tilde{\alpha}^{flip}$.

Sparsity and the Flip Test

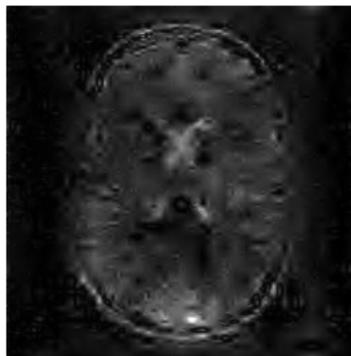
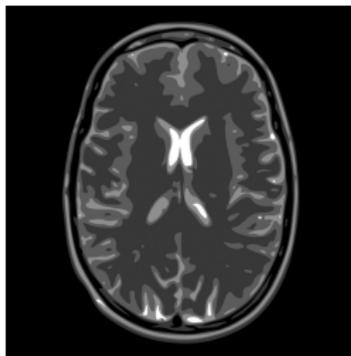
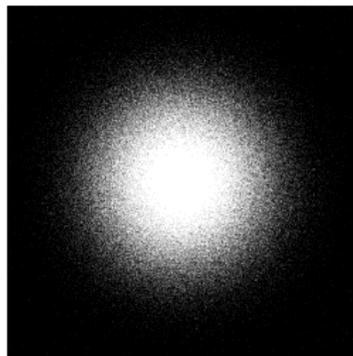
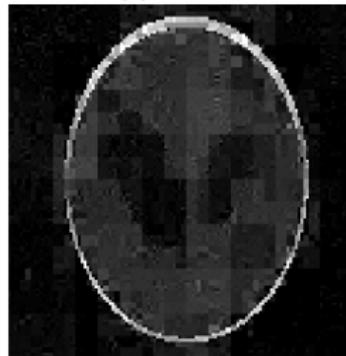
Ω



Standard Rec.



Flipped Rec.



Flip test for random Gaussian measurements

In the Fourier-wavelets case, we saw that Ω cannot depend on sparsity alone.

Actually, variable density sampling patterns exploit the fact that natural images are *asymptotically sparse* in wavelets.

However, random Gaussian measurements are insensitive to sparsity structure:

Standard Rec.



Flipped Rec.

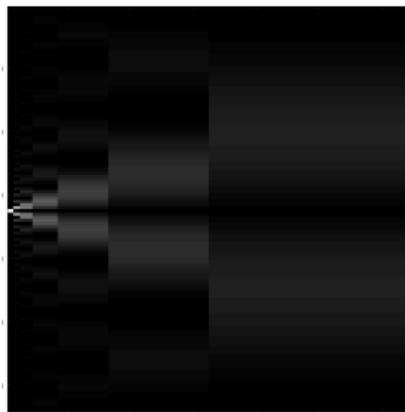


Asymptotic Incoherence

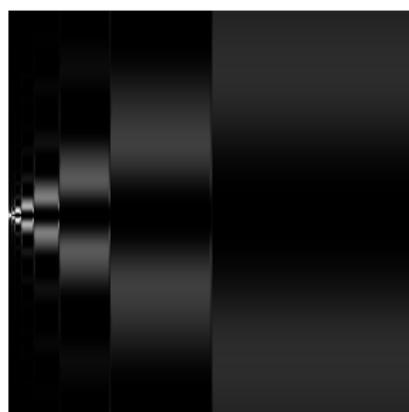
If $U = U_{df} U_{dw}^{-1}$ is the Fourier-wavelets matrix, then

$$\mu(P_N^\perp U), \mu(UP_N^\perp) = \mathcal{O}(N^{-1}).$$

Fourier to Haar



Fourier to DB4



Implication: Sample more at low Fourier frequencies where the local coherence is high and less at higher Fourier frequencies.

Recovery of Wavelet Coefficients from Partial Fourier Data

Theorem:

- ▶ $\{N_k\}_{k=1}^r$ and $\{M_k\}_{k=1}^r$ correspond to wavelet scales.
- ▶ The mother wavelet ψ has ν vanishing moments.
- ▶ There exists $\alpha \geq 1$, $C > 0$ such that $|\hat{\psi}(\xi)| \leq \frac{C}{(1+|\xi|)^\alpha}$ for all $\xi \in \mathbb{R}$.

One is guaranteed recovery of a wavelet sequence which is s_k -sparse in the k^{th} wavelet scale by choosing $\Omega = \Omega_1 \cup \dots \cup \Omega_r$ where $\Omega_k \subset \{N_{k-1} + 1, \dots, N_k\}$ are m_k samples chosen uniformly at random, with

$$\frac{m_k}{N_k - N_{k-1}} \gtrsim \frac{1}{N_{k-1}} \cdot \mathcal{L} \cdot \left(\hat{s}_k + \sum_{l=1}^{k-2} s_j \cdot 2^{-\alpha(k-l)} + \sum_{l=k+2}^r s_l \cdot 2^{-\nu(l-k)} \right)$$

where $\hat{s}_k = \max\{s_{k-1}, s_k, s_{k+1}\}$ and $\mathcal{L} = \log(\epsilon^{-1}) \cdot \log(KN\sqrt{s})$

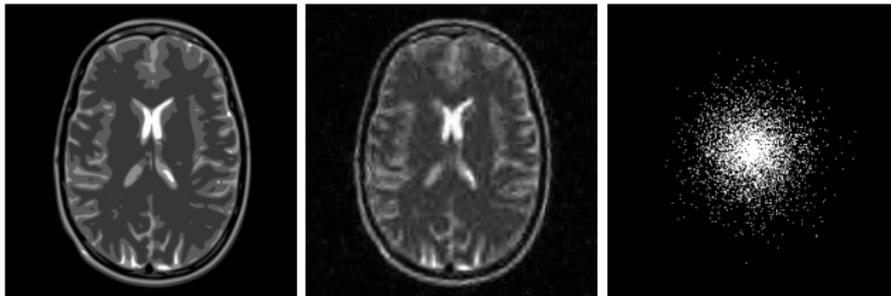
Resolution Dependence (5% samples, varying resolution)

Asymptotic sparsity and asymptotic incoherence are only witnessed when N is large. Thus, V. D. sampling only reaps their benefits for large values of N and the success of compressed sensing is **resolution dependent**.

256x256

Error:

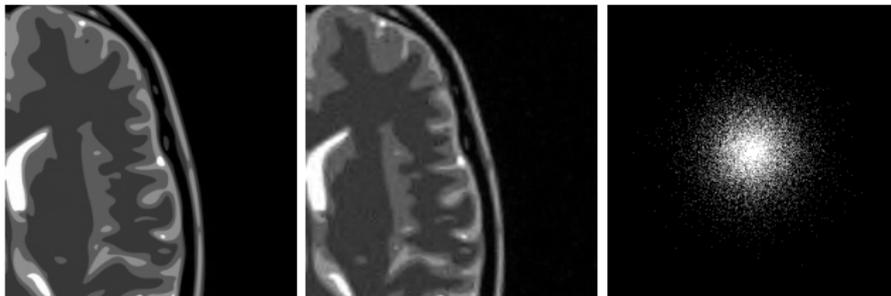
19.86%



512x512

Error:

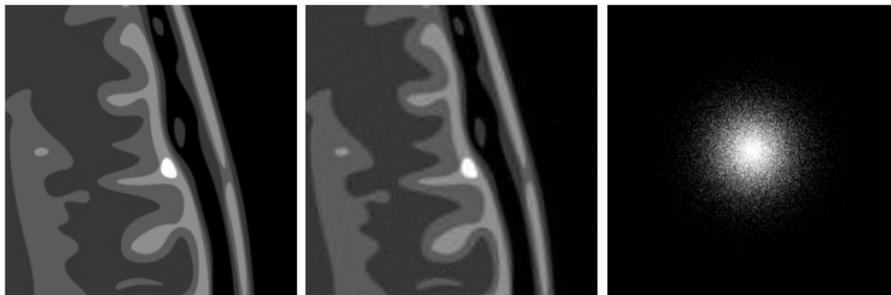
10.69%



Resolution Dependence (5% samples, varying resolution)

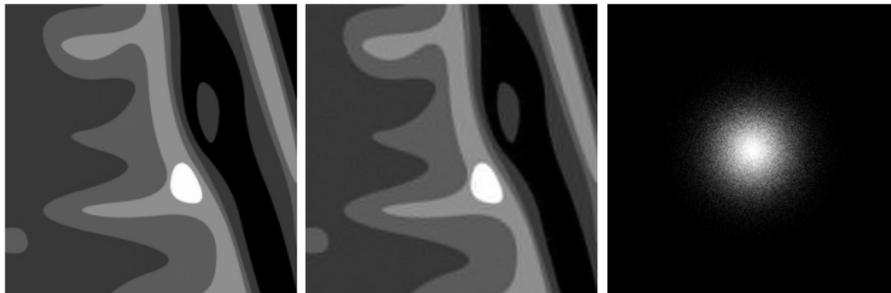
1024x1024

Error:
7.35%



2048x2048

Error:
4.87%



4096x4096

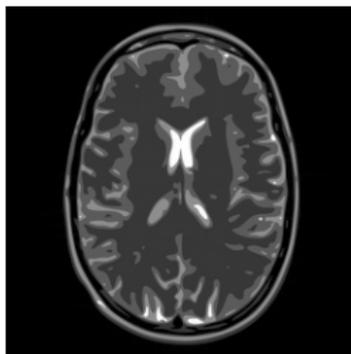
Error:
3.06%



Recovering Fine Details

At finer wavelet scales, the presence of sparsity and incoherence with Fourier samples allows us to subsample. Thus, compressed sensing allows one to **enhance fine details** without increasing the number of samples.

In the next example, consider the reconstruction of a 2048×2048 test phantom with details added at the finest wavelet scale.



Recovering Fine Details

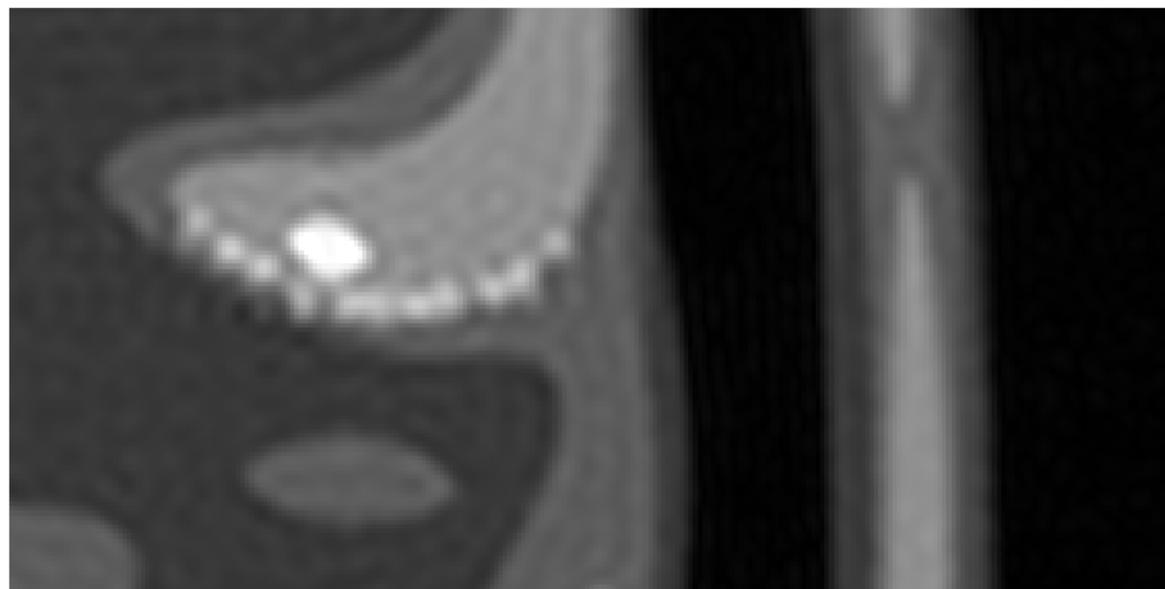


Figure: 2048×2048 linear reconstruction from the first 512×512 Fourier samples (6.25%)

Recovering Fine Details



Figure: 2048×2048 reconstruction from a multilevel scheme using 512×512 Fourier samples (6.25%)